

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1035	(702/57-59).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/10/24 12:04
L2	909	(702/81-84).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/10/24 12:37
L3	841	(702/89,108).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/10/24 12:41
L4	983	(702/117).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/10/24 12:42
L5	570	(702/118,119).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/10/24 12:45
L6	725	(702/120,121,123,125).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/10/24 12:45
L7	1304	(324/73.1).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/10/24 12:48
L8	256	(324/500,537,754,765).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:50
L9	268	(324/500,537,754,765).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:51
L10	57	(438/14,16,17).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:52
L11	96	(438/14,16,17).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:53
L12	0	(parametric and (test testing tested)).ti. and (load with wafer) same (automated or automatic\$) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:54
L13	10	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:55
L14	2	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with (controller controlling) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:57

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L15	1	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:57
L16	0	parametric adj test\$3 and synchroniz\$3 with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:58
L17	0	parametric adj test\$3 and synchronization with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:58
L18	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near (data instrumentation instrument) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:58
L19	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near file and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:58
L20	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same load near test and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:59
L21	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near (data instrumentation instrument) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:59
L22	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:59
L23	1	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:59
L24	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 12:59
L25	0	parametric adj test\$3 and state adj oscillator and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:00
L26	0	state adj oscillator same fault-tolerant same test\$3 and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:00
L27	0	state adj oscillator same fault-tolerant and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:00

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L28	0	state adj oscillator same test\$3 and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:00
L29	0	state adj oscillator same state near module and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:01
L30	0	state adj oscillator same state near object	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:01
L31	0	state adj oscillator same control adj state and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:01
L32	0	state adj oscillator same superstate and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:01
L33	2	parametric adj test\$3 and (control controlling) adj state and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:01
L34	0	(wafer adj electrical adj (test testing)) with (move moving movement) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:02
L35	0	(semiconductor wafer) and (move moving movement prober alignment) with (simultaneous\$2 concurrent\$2) with (initialize initialized initialization) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:02
L36	1	parametric adj test\$3 and concurrent adj operation and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:02
L37	0	parametric adj test\$3 and simultaneous adj operation	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:02
L38	1	alignment with initialization with (concurrent\$2 simultaneous\$2) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/10/24 13:03
L39	0	(semiconductor and parametric and test and control and concurrent).clm.	US-PGPUB	OR	ON	2006/10/24 13:03